

60V, 140A N-CHANNEL POWER MOSFET

GENERAL DESCRIPTION

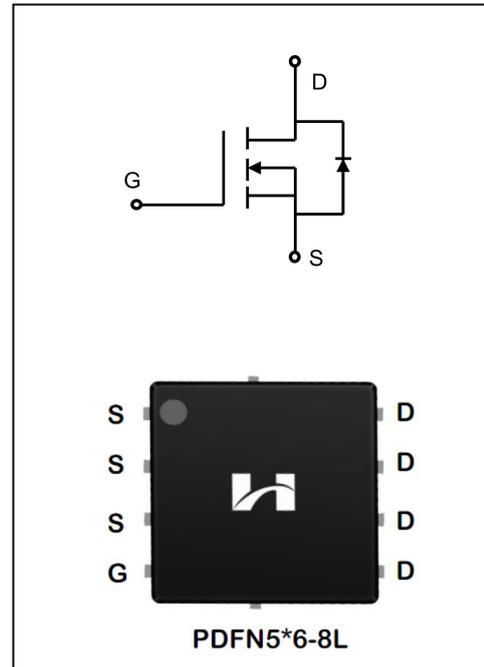
The SGM062R5T uses advanced SGT technology and design to provide excellent  $R_{DS(on)}$  with low gate charge. It can be used in a wide variety applications.

Features

- ◆  $V_{DS}=60V, I_D=140A$
- ◆  $R_{DS(on)}$   
 TYP:  $2.1m\Omega @V_{GS}=10V$   
 TYP:  $2.9m\Omega @V_{GS}=4.5V$

Applications

- ◆ PWM applications
- ◆ Load Switching
- ◆ Power management



ORDERING INFORMATION

Part No.	Package	Marking	Material	Packing
SGM062R5T	PDFN5*6-8L	SGM062R5T	Pb Free	Reel

ABSOLUTE MAXIMUM RATINGS (T<sub>J</sub>=25°C unless otherwise noted)

Characteristics		Symbol	Ratings	Unit
Drain-Source Voltage		V <sub>DS</sub>	60	V
Gate-Source Voltage		V <sub>GS</sub>	±20	V
Drain Current	T <sub>C</sub> = 25°C	I <sub>D</sub>	140	A
	T <sub>C</sub> = 100°C		98	
Drain Current Pulsed(Note 1)		I <sub>DM</sub>	560	A
Power Dissipation	T <sub>C</sub> = 25°C	P <sub>D</sub>	120	W
	T <sub>C</sub> = 100°C		0.96	
Single Pulsed Avalanche Energy (Note 2)		E <sub>AS</sub>	512	mJ
Operation Junction Temperature Range		T <sub>J</sub>	-55~+150	°C
Storage Temperature Range		T <sub>stg</sub>	-55~+150	°C
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		TL	300	°C

THERMAL CHARACTERISTICS

Characteristics	Symbol	MAX	Unit
Thermal Resistance, Junction-to-Case	R <sub>θJC</sub>	1.04	°C/W
Thermal Resistance, Junction-to-Ambient	R <sub>θJA</sub>	50	°C/W

ELECTRICAL CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Off Characteristics						
Drain -Source Breakdown Voltage	B <sub>VDS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	60	--	--	V
Drain-Source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V	--	--	1.0	uA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =20V, V <sub>DS</sub> =0V	--	--	100	nA
Gate-Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =-20V, V <sub>DS</sub> =0V	--	--	-100	
On Characteristics						
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> =250μA	1.0	1.8	2.5	V
Static Drain- Source On State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A	--	2.1	2.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =15A	--	2.9	3.4	
Dynamic Characteristics						
Gate Resistance	R <sub>g</sub>	V <sub>GS</sub> =0V; f=1.0MHZ	--	1.6	--	Ω
Input Capacitance	C <sub>iss</sub>	V <sub>DS</sub> =30V V <sub>GS</sub> =0V f=1.0MHZ	--	3040	--	pF
Output Capacitance	C <sub>oss</sub>		--	1507	--	
Reverse Transfer Capacitance	C <sub>rss</sub>		--	69	--	
Switching Characteristics						
Turn-on Delay Time	t <sub>d(on)</sub>	V <sub>DS</sub> =30V, V <sub>GS</sub> =10V R <sub>G</sub> =3.0Ω; I <sub>D</sub> =25A	--	22.8	--	ns
Turn-on Rise Time	t <sub>r</sub>		--	6.8	--	
Turn-off Delay Time	t <sub>d(off)</sub>		--	81	--	
Turn-off Fall Time	t <sub>f</sub>		--	28	--	

Total Gate Charge	$Q_g$	$V_{DS}=50V, I_D=50A$ $V_{GS}=10V$	--	92	--	nC
Gate-Source Charge	$Q_{gs}$		--	17	--	
Gate-Drain Charge	$Q_{gd}$		--	15	--	

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Characteristics	Symbol	Test conditions	Min.	Typ.	Max.	Unit
Continuous Source Current	$I_S$	Integral Reverse P-N Junction Diode in the MOSFET	--	--	140	A
Pulsed Source Current	$I_{SM}$		--	--	560	
Diode Forward Voltage	$V_{SD}$	$I_S=20A, V_{GS}=0V$	--	--	1.2	V
Reverse Recovery Time	$T_{rr}$	$I_F=20A, V_R=10V,$ $dI_F/dt=100A/\mu S$	--	67	--	ns
Reverse Recovery Charge	$Q_{rr}$		--	75	--	nC

1. Pulse width limited by maximum junction temperature
2.  $L=0.5mH, V_{DD}=30V, R_G=25\Omega, V_{GS}=10V,$  starting  $T_J=25^\circ C$
3. Pulse Test: Pulse width  $\leq 300\mu s,$  Duty cycle  $\leq 2\%$
4. Essentially independent of operating temperature

Typical Performance Characteristics

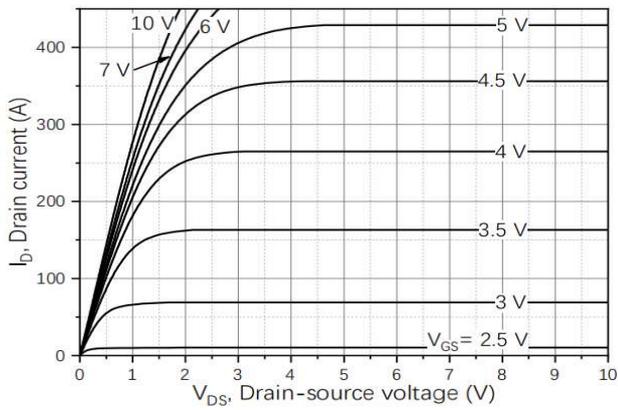


Figure1. Output Characteristics

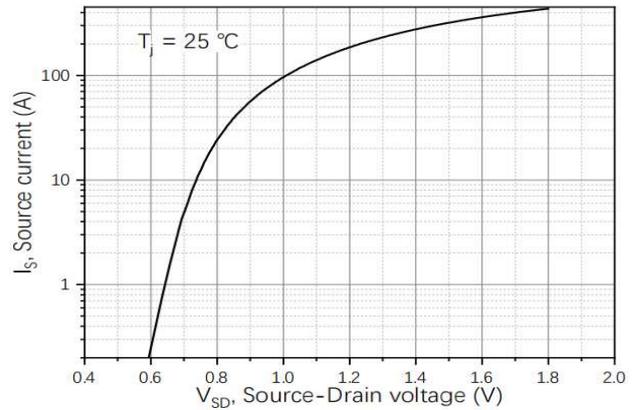


Figure2. Transfer Characteristics

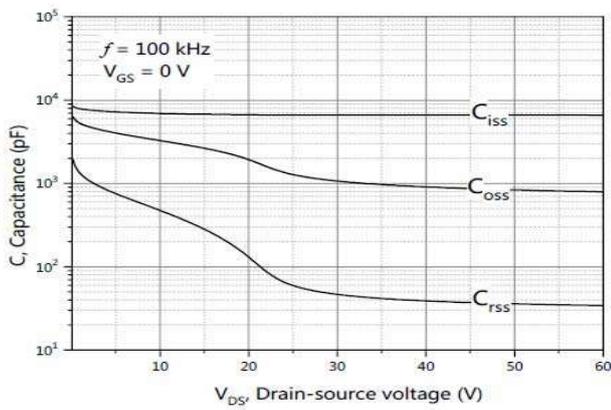


Figure3. Capacitance Characteristics

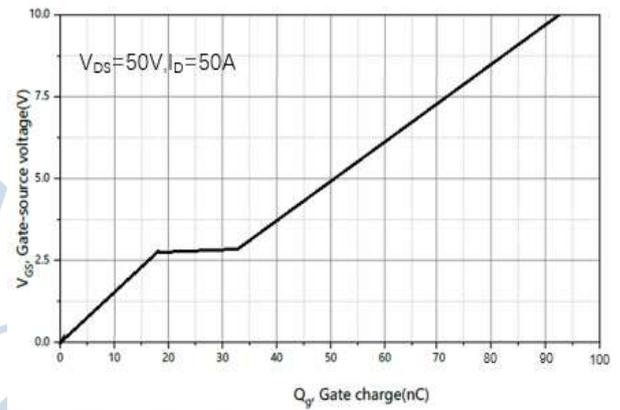


Figure4. Gate Charge

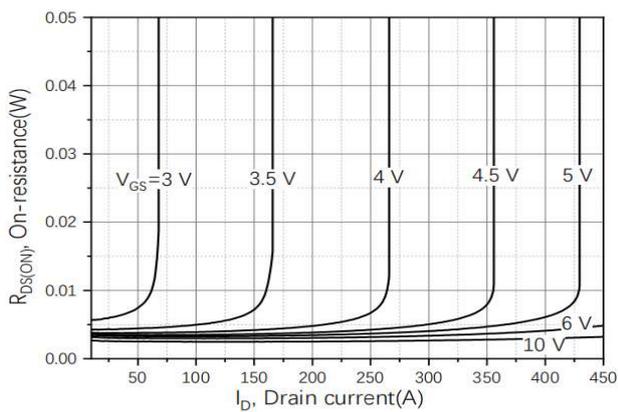


Figure5. Drain-Source on Resistance

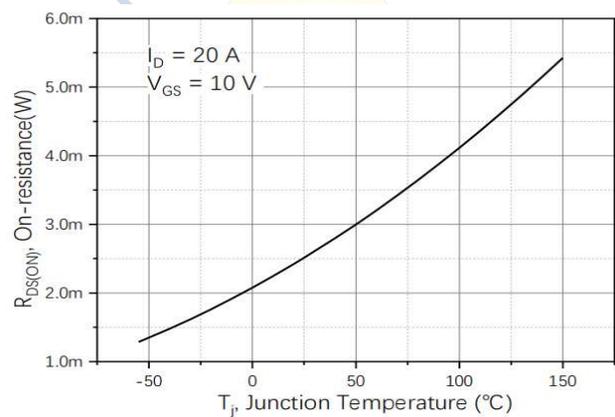


Figure6. Drain-Source on Resistance

Typical Performance Characteristics

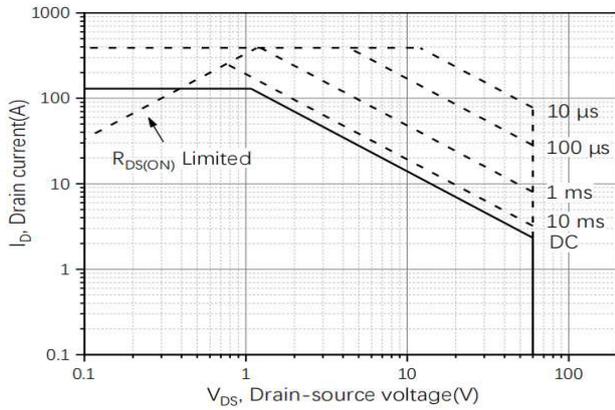


Figure7. Safe Operation Area

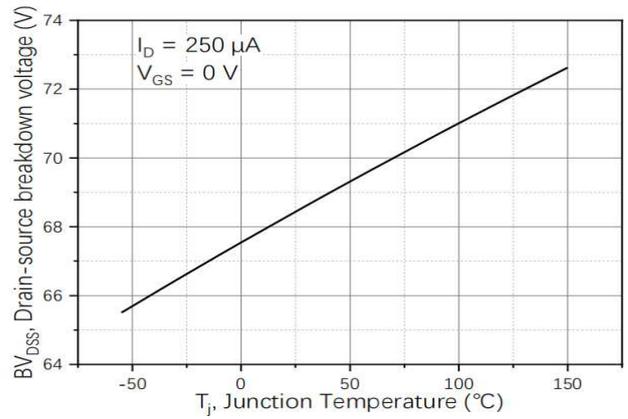


Figure8. Drain-source breakdown voltage

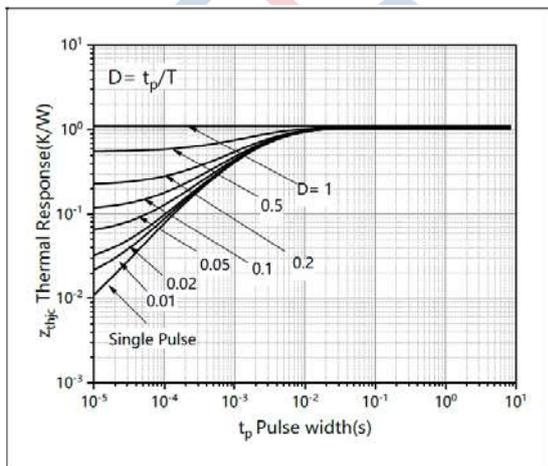
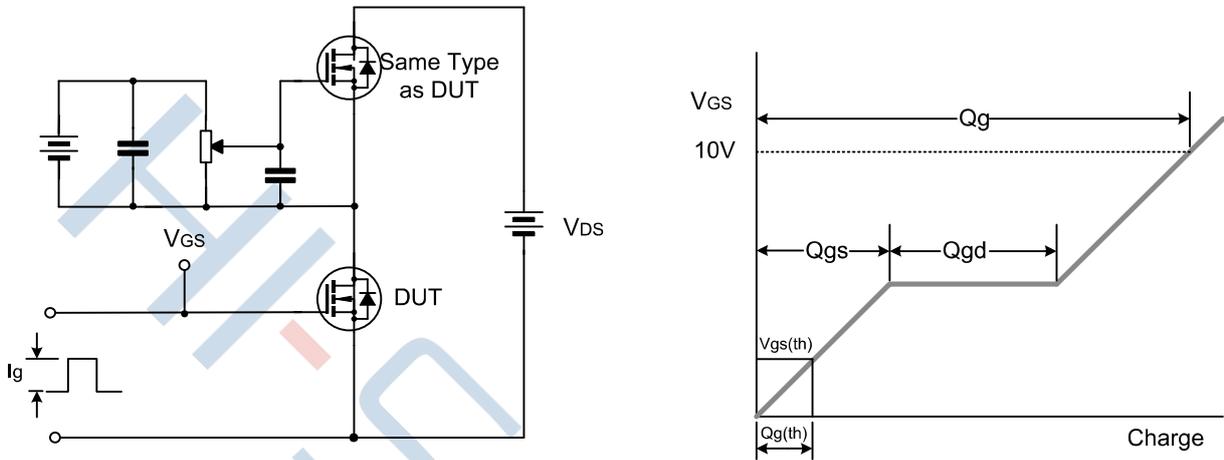


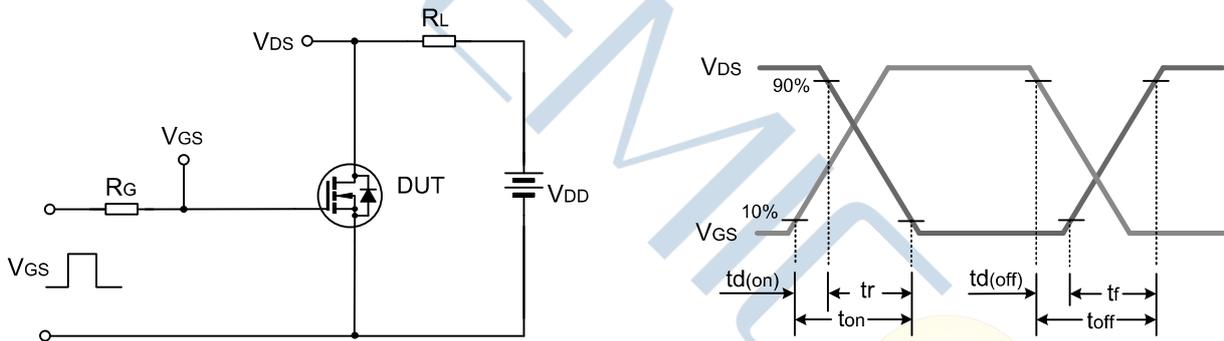
Figure 9. Transient thermal impedance

Test Circuit

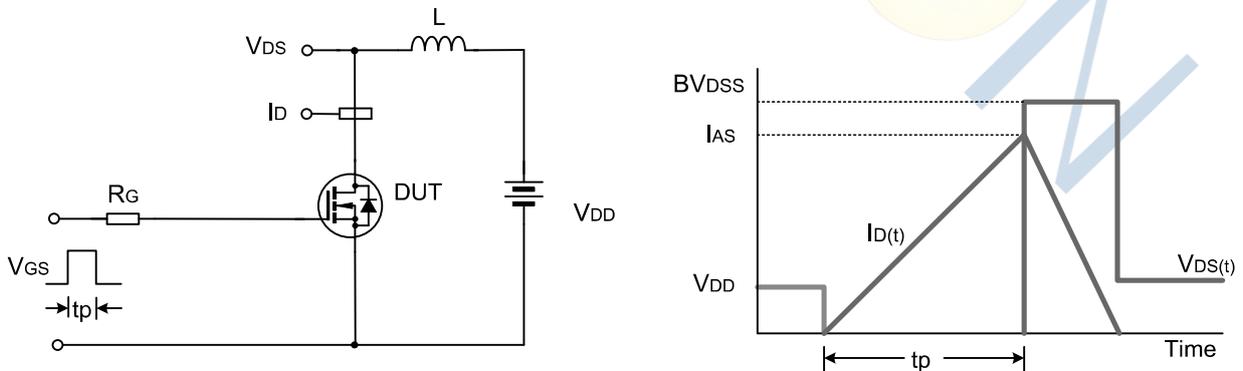
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveform

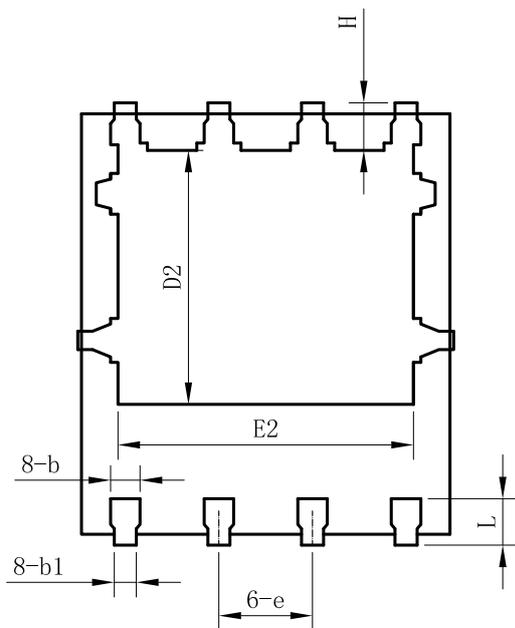
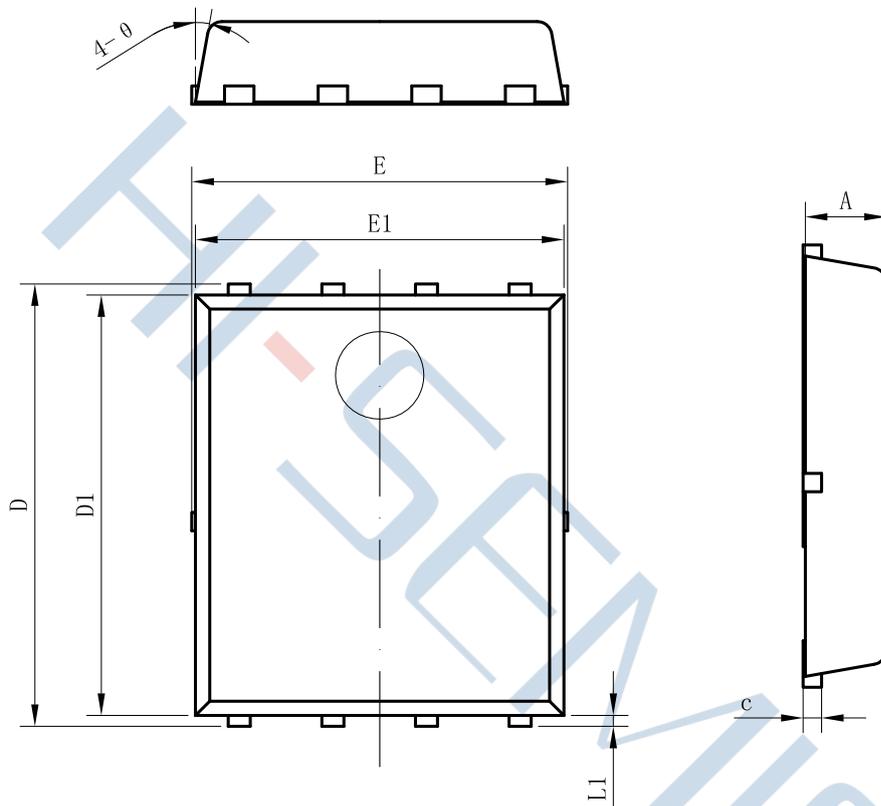


Unclamped Inductive Switching Test Circuit & Waveform



Package Dimensions of PDFN5\*6-8L

Unit:mm



COMMON DIMENSIONS  
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX
A	1.0	1.1	1.2
b	0.35	0.4	0.45
b1		(0.3)	
c	0.2	0.25	0.35
D	5.9	6.05	6.2
D1	5.65	5.75	5.85
D2		(3.475)	
E			5.2
E1	4.9	5	5.1
E2		(4.01)	
e		1.27BSC	
H	0.5	0.65	0.75
L	0.51	0.635	0.75
L1		0.15	
θ		10°	

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